



PATENT

ADDENDUM A

THE UNITED STATES PATENT AND TRADEMARK OFFICE

Assistant Commissioner for Patents
Washington, DC 20231

TC 2800 MAIL ROOM

DEC 18 2000

RECEIVED

REVOCATION AND SUBSTITUTE POWER OF ATTORNEY

Sir:

In the matter of the patent application identified in Exhibit A attached hereto, I, MICHAEL L. LYNCH, declare that I am a duly authorized designee of Micron Technology, Inc. ("Micron"), the ASSIGNEE of the entire right, title and interest in and to the patent application identified in Exhibit A attached hereto. Documentary evidence of chain of title from the original owner to ASSIGNEE has been or is concurrently being filed with and recorded by the United States Patent Office. The evidentiary documents referred to in the instant Revocation and Power of Attorney have been reviewed by the undersigned, and it is certified that, to the best of ASSIGNEE's knowledge and belief, title is held solely in and by Micron.

On behalf ASSIGNEE, I revoke all power of attorney heretofore given, and hereby appoint EDWARD W. BULCHIS, Reg. No. 26,847; JON F. TUTTLE, Reg. No. 25,713; PAUL T. MEIKLEJOHN, Reg. No. 26,569; GLENN P. RICKARDS, Reg. No. 29,428; DALE C. BARR, Reg. No. 40,498; KIMTON N. ENG, Reg. No. 43,605; DAVID E. BOONE, Reg. No. 27,857; SCOTT W. DOYLE, Reg. No. 39,176; REED R. HEIMBECHER, Reg. No. 36,353; JOHN T. KENNEDY, Reg. No. 42,717; GREGORY D. LEIBOLD, Reg. No. 36,408; GARY M. POLUMBUS, Reg. No. 25,364; THOMAS H. YOUNG, Reg. No. 25,796; W. ROBINSON H. CLARK, Reg. No. 41,530; GREGORY J. GLOVER, Reg. No. 34,173; JOHN K. HARROP, Reg. No. 41,817; CHRIS McWHINNEY, Reg. No. 42,875; ALDO NOTO, Reg. No. 35,628; MATTHEW PHILLIPS, Reg. No. 43,403; JOHN W. RYAN, Reg. No. 33,771; AMI P. SHAH, Reg. No. 42,143; SEAN S. WOODEN,

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ASSIGNEE:

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6-1-00
Date

By 
Michael L. Lynch
Chief Patent Counsel



Appl. No. Atty Dkt # Applicants Filed Title

09/083,835	500414.01 (660073.645)	Douglas D. Do and Jeff C. Johnson	22-May-98	Method for Measuring Features of a Semiconductor Device (As Amended)
09/629,022	500414.02	Douglas D. Do and Jeff C. Johnson	31-July-00	Method and Apparatus for Measuring Features of a Semiconductor Device